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Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	e200z0h
Core Size	32-Bit Single-Core
Speed	64MHz
Connectivity	CANbus, LINbus, SPI, UART/USART
Peripherals	DMA, POR, PWM, WDT
Number of I/O	64
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	20K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 3.6V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/spc560p40l3befbr

List of figures

Figure 1.	Block diagram (SPC560P40 full-featured configuration)	10
Figure 2.	64-pin LQFP pinout – Full featured configuration (top view)	29
Figure 3.	64-pin LQFP pinout – Airbag configuration (top view)	30
Figure 4.	100-pin LQFP pinout – Full featured configuration (top view)	31
Figure 5.	100-pin LQFP pinout – Airbag configuration (top view)	32
Figure 6.	Power supplies constraints ($-0.3\text{ V} \leq V_{DD_HV_IOx} \leq 6.0\text{ V}$)	47
Figure 7.	Independent ADC supply ($-0.3\text{ V} \leq V_{DD_HV_REG} \leq 6.0\text{ V}$)	48
Figure 8.	Power supplies constraints ($3.0\text{ V} \leq V_{DD_HV_IOx} \leq 5.5\text{ V}$)	51
Figure 9.	Independent ADC supply ($3.0\text{ V} \leq V_{DD_HV_REG} \leq 5.5\text{ V}$)	51
Figure 10.	Voltage regulator configuration	55
Figure 11.	Power-up typical sequence	58
Figure 12.	Power-down typical sequence	58
Figure 13.	Brown-out typical sequence	59
Figure 14.	Input DC electrical characteristics definition	63
Figure 15.	ADC characteristics and error definitions	68
Figure 16.	Input equivalent circuit	70
Figure 17.	Transient behavior during sampling phase	70
Figure 18.	Spectral representation of input signal	72
Figure 19.	Pad output delay	77
Figure 20.	Start-up reset requirements	78
Figure 21.	Noise filtering on reset signal	78
Figure 22.	JTAG test clock input timing	80
Figure 23.	JTAG test access port timing	81
Figure 24.	JTAG boundary scan timing	82
Figure 25.	Nexus output timing	83
Figure 26.	Nexus event trigger and test clock timing	83
Figure 27.	Nexus TDI, TMS, TDO timing	84
Figure 28.	External interrupt timing	85
Figure 29.	DSPI classic SPI timing – Master, CPHA = 0	86
Figure 30.	DSPI classic SPI timing – Master, CPHA = 1	87
Figure 31.	DSPI classic SPI timing – Slave, CPHA = 0	87
Figure 32.	DSPI classic SPI timing – Slave, CPHA = 1	88
Figure 33.	DSPI modified transfer format timing – Master, CPHA = 0	88
Figure 34.	DSPI modified transfer format timing – Master, CPHA = 1	89
Figure 35.	DSPI modified transfer format timing – Slave, CPHA = 0	89
Figure 36.	DSPI modified transfer format timing – Slave, CPHA = 1	90
Figure 37.	DSPI PCS Strobe (PCSS) timing	90
Figure 38.	LQFP100 package mechanical drawing	92
Figure 39.	LQFP64 package mechanical drawing	94
Figure 40.	Commercial product code structure	96

1 Introduction

1.1 Document overview

This document provides electrical specifications, pin assignments, and package diagrams for the SPC560P34/40 series of microcontroller units (MCUs). It also describes the device features and highlights important electrical and physical characteristics. For functional characteristics, refer to the device reference manual.

1.2 Description

This 32-bit system-on-chip (SoC) automotive microcontroller family is the latest achievement in integrated automotive application controllers. It belongs to an expanding range of automotive-focused products designed to address chassis applications—specifically, electrical hydraulic power steering (EHPS) and electric power steering (EPS)—as well as airbag applications.

This family is one of a series of next-generation integrated automotive microcontrollers based on the Power Architecture technology.

The advanced and cost-efficient host processor core of this automotive controller family complies with the Power Architecture embedded category. It operates at speeds of up to 64 MHz and offers high performance processing optimized for low power consumption. It capitalizes on the available development infrastructure of current Power Architecture devices and is supported with software drivers, operating systems and configuration code to assist with users implementations.

1.3 Device comparison

[Table 2](#) provides a summary of different members of the SPC560P34/SPC560P40 family and their features—relative to full-featured version—to enable a comparison among the family members and an understanding of the range of functionality offered within this family.

Table 2. SPC560P34/SPC560P40 device comparison

Feature	SPC560P34 Full-featured	SPC560P40 Full-featured
Code flash memory (with ECC)	192 KB	256 KB
Data flash memory / EE option (with ECC)	64 KB	
SRAM (with ECC)	12 KB	20 KB
Processor core	32-bit e200z0h	
Instruction set	VLE (variable length encoding)	
CPU performance	0–64 MHz	
FMPLL (frequency-modulated phase-locked loop) module	1	
INTC (interrupt controller) channels	120	
PIT (periodic interrupt timer)	1 (with four 32-bit timers)	

Table 2. SPC560P34/SPC560P40 device comparison (continued)

Feature		SPC560P34 Full-featured	SPC560P40 Full-featured
eDMA (enhanced direct memory access) channels		16	
FlexCAN (controller area network)		1 ⁽¹⁾	2 ^{(1),(2)}
Safety port		No	Yes (via second FlexCAN module)
FCU (fault collection unit)		Yes	
CTU (cross triggering unit)		Yes	Yes
eTimer		1 (16-bit, 6 channels)	
FlexPWM (pulse-width modulation) channels		8 (capture capability not supported)	8 (capture capability not supported)
Analog-to-digital converter (ADC)		1 (10-bit, 16 channels)	
LINFlex		2 (1 × Master/Slave, 1 × Master only)	2 (1 × Master/Slave, 1 × Master only)
DSPI (deserial serial peripheral interface)		2	3
CRC (cyclic redundancy check) unit		Yes	
Junction temperature sensor		No	
JTAG controller		Yes	
Nexus port controller (NPC)		Yes (Nexus Class 1)	
Supply	Digital power supply ⁽³⁾	3.3 V or 5 V single supply with external transistor	
	Analog power supply	3.3 V or 5 V	
	Internal RC oscillator	16 MHz	
	External crystal oscillator	4–40 MHz	
Packages		LQFP64 LQFP100	
Temperature	Standard ambient temperature	–40 to 125 °C	

1. Each FlexCAN module has 32 message buffers.

2. One FlexCAN module can act as a safety port with a bit rate as high as 8 Mbit/s at 64 MHz.

3. The different supply voltages vary according to the part number ordered.

SPC560P34/SPC560P40 is available in two configurations having different features: Full-featured and airbag. [Table 3](#) shows the main differences between the two versions of the SPC560P40 MCU.

Table 4. SPC560P34/SPC560P40 series block summary

Block	Function
Analog-to-digital converter (ADC)	Multi-channel, 10-bit analog-to-digital converter
Boot assist module (BAM)	Block of read-only memory containing VLE code which is executed according to the boot mode of the device
Clock generation module (MC_CGM)	Provides logic and control required for the generation of system and peripheral clocks
Controller area network (FlexCAN)	Supports the standard CAN communications protocol
Cross triggering unit (CTU)	Enables synchronization of ADC conversions with a timer event from the eMIOS or from the PIT
Crossbar switch (XBAR)	Supports simultaneous connections between two master ports and three slave ports; supports a 32-bit address bus width and a 32-bit data bus width
Cyclic redundancy check (CRC)	CRC checksum generator
Deserial serial peripheral interface (DSPI)	Provides a synchronous serial interface for communication with external devices
Enhanced direct memory access (eDMA)	Performs complex data transfers with minimal intervention from a host processor via “n” programmable channels
Enhanced timer (eTimer)	Provides enhanced programmable up/down modulo counting
Error correction status module (ECSM)	Provides a myriad of miscellaneous control functions for the device including program-visible information about configuration and revision levels, a reset status register, wakeup control for exiting sleep modes, and optional features such as information on memory errors reported by error-correcting codes
External oscillator (XOSC)	Provides an output clock used as input reference for FMPLL_0 or as reference clock for specific modules depending on system needs
Fault collection unit (FCU)	Provides functional safety to the device
Flash memory	Provides non-volatile storage for program code, constants and variables
Frequency-modulated phase-locked loop (FMPLL)	Generates high-speed system clocks and supports programmable frequency modulation
Interrupt controller (INTC)	Provides priority-based preemptive scheduling of interrupt requests
JTAG controller	Provides the means to test chip functionality and connectivity while remaining transparent to system logic when not in test mode
LINFlex controller	Manages a high number of LIN (Local Interconnect Network protocol) messages efficiently with a minimum of CPU load
Mode entry module (MC_ME)	Provides a mechanism for controlling the device operational mode and mode transition sequences in all functional states; also manages the power control unit, reset generation module and clock generation module, and holds the configuration, control and status registers accessible for applications
Periodic interrupt timer (PIT)	Produces periodic interrupts and triggers
Peripheral bridge (PBRIDGE)	Is the interface between the system bus and on-chip peripherals
Power control unit (MC_PCU)	Reduces the overall power consumption by disconnecting parts of the device from the power supply via a power switching device; device components are grouped into sections called “power domains” which are controlled by the PCU

1.5 Feature details

1.5.1 High performance e200z0 core processor

The e200z0 Power Architecture core provides the following features:

- High performance e200z0 core processor for managing peripherals and interrupts
- Single issue 4-stage pipeline in-order execution 32-bit Power Architecture CPU
- Harvard architecture
- Variable length encoding (VLE), allowing mixed 16- and 32-bit instructions
 - Results in smaller code size footprint
 - Minimizes impact on performance
- Branch processing acceleration using lookahead instruction buffer
- Load/store unit
 - 1-cycle load latency
 - Misaligned access support
 - No load-to-use pipeline bubbles
- Thirty-two 32-bit general purpose registers (GPRs)
- Separate instruction bus and load/store bus Harvard architecture
- Hardware vectored interrupt support
- Reservation instructions for implementing read-modify-write constructs
- Long cycle time instructions, except for guarded loads, do not increase interrupt latency
- Extensive system development support through Nexus debug port
- Non-maskable interrupt support

1.5.2 Crossbar switch (XBAR)

The XBAR multi-port crossbar switch supports simultaneous connections between three master ports and three slave ports. The crossbar supports a 32-bit address bus width and a 32-bit data bus width.

The crossbar allows for two concurrent transactions to occur from any master port to any slave port; but one of those transfers must be an instruction fetch from internal flash memory. If a slave port is simultaneously requested by more than one master port, arbitration logic will select the higher priority master and grant it ownership of the slave port. All other masters requesting that slave port will be stalled until the higher priority master completes its transactions. Requesting masters will be treated with equal priority and will be granted access a slave port in round-robin fashion, based upon the ID of the last master to be granted access.

The flash memory module provides the following features:

- As much as 320 KB flash memory
 - 6 blocks (32 KB + 2×16 KB + 32 KB + 32 KB + 128 KB) code flash memory
 - 4 blocks (16 KB + 16 KB + 16 KB + 16 KB) data flash memory
 - Full Read-While-Write (RWW) capability between code flash memory and data flash memory
- Four 128-bit wide prefetch buffers to provide single cycle in-line accesses (prefetch buffers can be configured to prefetch code or data or both)
- Typical flash memory access time: no wait-state for buffer hits, 2 wait-states for page buffer miss at 64 MHz
- Hardware managed flash memory writes handled by 32-bit RISC Krypton engine
- Hardware and software configurable read and write access protections on a per-master basis
- Configurable access timing allowing use in a wide range of system frequencies
- Multiple-mapping support and mapping-based block access timing (up to 31 additional cycles) allowing use for emulation of other memory types
- Software programmable block program/erase restriction control
- Erase of selected block(s)
- Read page sizes
 - Code flash memory: 128 bits (4 words)
 - Data flash memory: 32 bits (1 word)
- ECC with single-bit correction, double-bit detection for data integrity
 - Code flash memory: 64-bit ECC
 - Data flash memory: 32-bit ECC
- Embedded hardware program and erase algorithm
- Erase suspend and program abort
- Censorship protection scheme to prevent flash memory content visibility
- Hardware support for EEPROM emulation

1.5.5 Static random access memory (SRAM)

The SPC560P34/SPC560P40 SRAM module provides up to 20 KB of general-purpose memory.

The SRAM module provides the following features:

- Supports read/write accesses mapped to the SRAM from any master
- Up to 20 KB general purpose SRAM
- Supports byte (8-bit), half word (16-bit), and word (32-bit) writes for optimal use of memory
- Typical SRAM access time: no wait-state for reads and 32-bit writes; 1 wait-state for 8- and 16-bit writes if back-to-back with a read to same memory block

1.5.8 System clocks and clock generation

The following list summarizes the system clock and clock generation on the SPC560P34/SPC560P40:

- Lock detect circuitry continuously monitors lock status
- Loss of clock (LOC) detection for PLL outputs
- Programmable output clock divider ($\div 1$, $\div 2$, $\div 4$, $\div 8$)
- FlexPWM module and eTimer module running at the same frequency as the e200z0h core
- Internal 16 MHz RC oscillator for rapid start-up and safe mode: supports frequency trimming by user application

1.5.9 Frequency-modulated phase-locked loop (FMPLL)

The FMPLL allows the user to generate high speed system clocks from a 4–40 MHz input clock. Further, the FMPLL supports programmable frequency modulation of the system clock. The PLL multiplication factor, output clock divider ratio are all software configurable.

The FMPLL has the following major features:

- Input clock frequency: 4–40 MHz
- Maximum output frequency: 64 MHz
- Voltage controlled oscillator (VCO)—frequency 256–512 MHz
- Reduced frequency divider (RFD) for reduced frequency operation without forcing the FMPLL to relock
- Frequency-modulated PLL
 - Modulation enabled/disabled through software
 - Triangle wave modulation
- Programmable modulation depth ($\pm 0.25\%$ to $\pm 4\%$ deviation from center frequency): programmable modulation frequency dependent on reference frequency
- Self-clocked mode (SCM) operation

1.5.10 Main oscillator

The main oscillator provides these features:

- Input frequency range: 4–40 MHz
- Crystal input mode or oscillator input mode
- PLL reference

1.5.11 Internal RC oscillator

This device has an RC ladder phase-shift oscillator. The architecture uses constant current charging of a capacitor. The voltage at the capacitor is compared by the stable bandgap reference voltage.

1.5.31 On-chip voltage regulator (VREG)

The on-chip voltage regulator module provides the following features:

- Uses external NPN (negative-positive-negative) transistor
- Regulates external 3.3 V/5.0 V down to 1.2 V for the core logic
- Low voltage detection on the internal 1.2 V and I/O voltage 3.3 V

2.2 Pin description

The following sections provide signal descriptions and related information about the functionality and configuration of the SPC560P34/SPC560P40 devices.

2.2.1 Power supply and reference voltage pins

[Table 5](#) lists the power supply and reference voltage for the SPC560P34/SPC560P40 devices.

Table 5. Supply pins

Supply		Pin	
Symbol	Description	64-pin	100-pin
VREG control and power supply pins. Pins available on 64-pin and 100-pin packages			
BCTRL	Voltage regulator external NPN ballast base control pin	31	47
$V_{DD_HV_REG}$ (3.3 V or 5.0 V)	Voltage regulator supply voltage	32	50
ADC_0 reference and supply voltage. Pins available on 64-pin and 100-pin packages			
$V_{DD_HV_ADC0}^{(1)}$	ADC_0 supply and high reference voltage	28	39
$V_{SS_HV_ADC0}$	ADC_0 ground and low reference voltage	29	40
Power supply pins (3.3 V or 5.0 V). Pins available on 64-pin and 100-pin packages			
$V_{DD_HV_IO1}$	Input/output supply voltage	6	13
$V_{SS_HV_IO1}$	Input/output ground	7	14
$V_{DD_HV_IO2}$	Input/output supply voltage and data Flash memory supply voltage	40	63
$V_{SS_HV_IO2}$	Input/output ground and Flash memory HV ground	39	62
$V_{DD_HV_IO3}$	Input/output supply voltage and code Flash memory supply voltage	55	87
$V_{SS_HV_IO3}$	Input/output ground and code Flash memory HV ground	56	88
$V_{DD_HV_OSC}$	Crystal oscillator amplifier supply voltage	9	16
$V_{SS_HV_OSC}$	Crystal oscillator amplifier ground	10	17
Power supply pins (1.2 V). Pins available on 64-pin and 100-pin packages			
$V_{DD_LV_COR0}$	1.2 V supply pins for core logic and PLL. Decoupling capacitor must be connected between these pins and the nearest $V_{SS_LV_COR}$ pin.	16	25
$V_{SS_LV_COR0}$	1.2 V supply pins for core logic and PLL. Decoupling capacitor must be connected between these pins and the nearest $V_{DD_LV_COR}$ pin.	15	24
$V_{DD_LV_COR1}$	1.2 V supply pins for core logic and data Flash. Decoupling capacitor must be connected between these pins and the nearest $V_{SS_LV_COR}$ pin.	42	65
$V_{SS_LV_COR1}$	1.2 V supply pins for core logic and data Flash. Decoupling capacitor must be connected between these pins and the nearest $V_{DD_LV_COR}$ pin.	43	66

Table 5. Supply pins (continued)

Supply		Pin	
Symbol	Description	64-pin	100-pin
$V_{DD_LV_COR2}$	1.2 V supply pins for core logic and code Flash. Decoupling capacitor must be connected between these pins and the nearest $V_{SS_LV_COR}$ pin.	58	92
$V_{SS_LV_COR2}$	1.2 V supply pins for core logic and code Flash. Decoupling capacitor must be connected between these pins and the nearest $V_{DD_LV_COR}$ pin.	59	93

1. Analog supply/ground and high/low reference lines are internally physically separate, but are shorted via a double-bonding connection on $V_{DD_HV_ADCx}/V_{SS_HV_ADCx}$ pins.

2.2.2 System pins

[Table 6](#) and [Table 7](#) contain information on pin functions for the SPC560P34/SPC560P40 devices. The pins listed in [Table 6](#) are single-function pins. The pins shown in [Table 7](#) are multi-function pins, programmable via their respective pad configuration register (PCR) values.

Table 6. System pins

Symbol	Description	Direction	Pad speed ⁽¹⁾		Pin	
			SRC = 0	SRC = 1	64-pin	100-pin
Dedicated pins						
NMI	Non-maskable Interrupt	Input only	Slow	—	1	1
XTAL	Analog output of the oscillator amplifier circuit—needs to be grounded if oscillator is used in bypass mode	—	—	—	11	18
EXTAL	Analog input of the oscillator amplifier circuit, when the oscillator is not in bypass mode Analog input for the clock generator when the oscillator is in bypass mode	—	—	—	12	19
TDI	JTAG test data input	Input only	Slow	—	35	58
TMS	JTAG state machine control	Input only	Slow	—	36	59
TCK	JTAG clock	Input only	Slow	—	37	60
TDO	JTAG test data output	Output only	Slow	Fast	38	61
Reset pin						
$\overline{\text{RESET}}$	Bidirectional reset with Schmitt trigger characteristics and noise filter	Bidirectional	Medium	—	13	20
Test pin						
VPP_TEST	Pin for testing purpose only. To be tied to ground in normal operating mode.	—	—	—	47	74

1. SRC values refer to the value assigned to the Slew Rate Control bits of the pad configuration register.

Table 7. Pin muxing (continued)

Port pin	PCR register	Alternate function ^{(1),(2)}	Functions	Peripheral ⁽³⁾	I/O direction ⁽⁴⁾	Pad speed ⁽⁵⁾		Pin	
						SRC = 0	SRC = 1	64-pin	100-pin
C[1]	PCR[33]	ALT0 ALT1 ALT2 ALT3 —	GPIO[33] — — — AN[2]	SIUL — — — ADC_0	Input only	—	—	19	28
C[2]	PCR[34]	ALT0 ALT1 ALT2 ALT3 —	GPIO[34] — — — AN[3]	SIUL — — — ADC_0	Input only	—	—	21	30
C[3]	PCR[35]	ALT0 ALT1 ALT2 ALT3 —	GPIO[35] CS1 — TXD EIRQ[21]	SIUL DSPI_0 — LIN_1 SIUL	I/O O — O I	Slow	Medium	—	10
C[4]	PCR[36]	ALT0 ALT1 ALT2 ALT3 —	GPIO[36] CS0 X[1] DEBUG[4] EIRQ[22]	SIUL DSPI_0 FlexPWM_0 SSCM SIUL	I/O I/O O — I	Slow	Medium	—	5
C[5]	PCR[37]	ALT0 ALT1 ALT2 ALT3 —	GPIO[37] SCK — DEBUG[5] EIRQ[23]	SIUL DSPI_0 — SSCM SIUL	I/O I/O — — I	Slow	Medium	—	7
C[6]	PCR[38]	ALT0 ALT1 ALT2 ALT3 —	GPIO[38] SOUT B[1] DEBUG[6] EIRQ[24]	SIUL DSPI_0 FlexPWM_0 SSCM SIUL	I/O O O — I	Slow	Medium	—	98
C[7]	PCR[39]	ALT0 ALT1 ALT2 ALT3 —	GPIO[39] — A[1] DEBUG[7] SIN	SIUL — FlexPWM_0 SSCM DSPI_0	I/O — O — I	Slow	Medium	—	9
C[8]	PCR[40]	ALT0 ALT1 ALT2 ALT3	GPIO[40] CS1 — CS6	SIUL DSPI_1 — DSPI_0	I/O O — O	Slow	Medium	57	91

Table 7. Pin muxing (continued)

Port pin	PCR register	Alternate function ^{(1),(2)}	Functions	Peripheral ⁽³⁾	I/O direction ⁽⁴⁾	Pad speed ⁽⁵⁾		Pin	
						SRC = 0	SRC = 1	64-pin	100-pin
E[4]	PCR[68]	ALT0 ALT1 ALT2 ALT3 —	GPIO[68] — — — AN[7]	SIUL — — — ADC_0	Input only	—	—	—	44
E[5]	PCR[69]	ALT0 ALT1 ALT2 ALT3 —	GPIO[69] — — — AN[8]	SIUL — — — ADC_0	Input only	—	—	—	43
E[6]	PCR[70]	ALT0 ALT1 ALT2 ALT3 —	GPIO[70] — — — AN[9]	SIUL — — — ADC_0	Input only	—	—	—	45
E[7]	PCR[71]	ALT0 ALT1 ALT2 ALT3 —	GPIO[71] — — — AN[10]	SIUL — — — ADC_0	Input only	—	—	—	41

1. ALT0 is the primary (default) function for each port after reset.
2. Alternate functions are chosen by setting the values of the PCR.PA bitfields inside the SIU module. PCR.PA = 00 → ALT0; PCR.PA = 01 → ALT1; PCR.PA = 10 → ALT2; PCR.PA = 11 → ALT3. This is intended to select the output functions; to use one of the input functions, the PCR.IBE bit must be written to '1', regardless of the values selected in the PCR.PA bitfields. For this reason, the value corresponding to an input only function is reported as "—".
3. Module included on the MCU.
4. Multiple inputs are routed to all respective modules internally. The input of some modules must be configured by setting the values of the PSMIO.PADSELx bitfields inside the SIUL module.
5. Programmable via the SRC (Slew Rate Control) bits in the respective Pad Configuration Register.
6. ADC0.AN emulates ADC1.AN. This feature is used to provide software compatibility between SPC560P34/SPC560P40 and SPC560P50. Refer to ADC chapter of reference manual for more details.

Table 10. Recommended operating conditions (5.0 V) (continued)

Symbol		Parameter	Conditions	Value		Unit
				Min	Max ⁽¹⁾	
V _{DD_HV_ADC0}	SR	5.0 V ADC_0 supply and high reference voltage	—	4.5	5.5	V
			Relative to V _{DD_HV_REG}	V _{DD_HV_REG} – 0.1	—	
V _{SS_HV_ADC0}	SR	ADC_0 ground and low reference voltage	—	0	0	V
V _{DD_LV_REGCOR} ^{(3),(4)}	CC	Internal supply voltage	—	—	—	V
V _{SS_LV_REGCOR} ⁽³⁾	SR	Internal reference voltage	—	0	0	V
V _{DD_LV_CORx} ^{(3),(4)}	CC	Internal supply voltage	—	—	—	V
V _{SS_LV_CORx} ⁽³⁾	SR	Internal reference voltage	—	0	0	V
T _A	SR	Ambient temperature under bias	f _{CPU} = 60 MHz	–40	125	°C
			f _{CPU} = 64 MHz	–40	105	°C

- Full functionality cannot be guaranteed when voltage drops below 4.5 V. In particular, ADC electrical characteristics and I/Os DC electrical specification may not be guaranteed.
- The difference between each couple of voltage supplies must be less than 100 mV, $|V_{DD_HV_IOx} - V_{DD_HV_IOx}| < 100$ mV.
- To be connected to emitter of external NPN. Low voltage supplies are not under user control—they are produced by an on-chip voltage regulator—but for the device to function properly the low voltage grounds (V_{SS_LV_XXX}) must be shorted to high voltage grounds (V_{SS_HV_XXX}) and the low voltage supply pins (V_{DD_LV_XXX}) must be connected to the external ballast emitter.
- The low voltage supplies (V_{DD_LV_XXX}) are not all independent.
 - V_{DD_LV_COR1} and V_{DD_LV_COR2} are shorted internally via double bonding connections with lines that provide the low voltage supply to the data flash memory module. Similarly, V_{SS_LV_COR1} and V_{SS_LV_COR2} are internally shorted.
 - V_{DD_LV_REGCOR} and V_{DD_LV_RECORx} are physically shorted internally, as are V_{SS_LV_REGCOR} and V_{SS_LV_CORx}.

Table 11. Recommended operating conditions (3.3 V)

Symbol		Parameter	Conditions	Value		Unit
				Min	Max ⁽¹⁾	
V _{SS}	SR	Device ground	—	0	0	V
V _{DD_HV_IOx} ⁽²⁾	SR	3.3 V input/output supply voltage	—	3.0	3.6	V
V _{SS_HV_IOx}	SR	Input/output ground voltage	—	0	0	V
V _{DD_HV_OSC}	SR	3.3 V crystal oscillator amplifier supply voltage	—	3.0	3.6	V
			Relative to V _{DD_HV_IOx}	V _{DD_HV_IOx} – 0.1	V _{DD_HV_IOx} + 0.1	
V _{SS_HV_OSC}	SR	3.3 V crystal oscillator amplifier reference voltage	—	0	0	V

3.8.2 Voltage monitor electrical characteristics

The device implements a power on reset module to ensure correct power-up initialization, as well as three low voltage detectors to monitor the V_{DD} and the V_{DD_LV} voltage while device is supplied:

- POR monitors V_{DD} during the power-up phase to ensure device is maintained in a safe reset state
- LVDHV3 monitors V_{DD} to ensure device reset below minimum functional supply
- LVDHV5 monitors V_{DD} when application uses device in the $5.0\text{ V} \pm 10\%$ range
- LVDLVCOR monitors low voltage digital power domain

Table 17. Low voltage monitor electrical characteristics

Symbol	C	Parameter	Conditions ⁽¹⁾	Value		Unit
				Min	Max	
V_{PORH}	T	Power-on reset threshold	—	1.5	2.7	V
V_{PORUP}	P	Supply for functional POR module	$T_A = 25\text{ }^{\circ}\text{C}$	1.0	—	V
$V_{REGLVDMOK_H}$	P	Regulator low voltage detector high threshold	—	—	2.95	V
$V_{REGLVDMOK_L}$	P	Regulator low voltage detector low threshold	—	2.6	—	V
$V_{FLLVDMOK_H}$	P	Flash low voltage detector high threshold	—	—	2.95	V
$V_{FLLVDMOK_L}$	P	Flash low voltage detector low threshold	—	2.6	—	V
$V_{IOLVDMOK_H}$	P	I/O low voltage detector high threshold	—	—	2.95	V
$V_{IOLVDMOK_L}$	P	I/O low voltage detector low threshold	—	2.6	—	V
$V_{IOLVDM5OK_H}$	P	I/O 5 V low voltage detector high threshold	—	—	4.4	V
$V_{IOLVDM5OK_L}$	P	I/O 5 V low voltage detector low threshold	—	3.8	—	V
$V_{MLVDDOK_H}$	P	Digital supply low voltage detector high	—	—	1.145	V
$V_{MLVDDOK_L}$	P	Digital supply low voltage detector low	—	1.08	—	V

1. $V_{DD} = 3.3\text{ V} \pm 10\% / 5.0\text{ V} \pm 10\%$, $T_A = -40\text{ }^{\circ}\text{C}$ to $T_{A\text{ MAX}}$, unless otherwise specified

3.9 Power up/down sequencing

To prevent an overstress event or a malfunction within and outside the device, the SPC560P34/SPC560P40 implements the following sequence to ensure each module is started only when all conditions for switching it ON are available:

- A POWER_ON module working on voltage regulator supply controls the correct start-up of the regulator. This is a key module ensuring safe configuration for all voltage regulator functionality when supply is below 1.5 V. Associated POWER_ON (or POR) signal is active low.
- Several low voltage detectors, working on voltage regulator supply monitor the voltage of the critical modules (voltage regulator, I/Os, flash memory and low voltage domain). LVDs are gated low when POWER_ON is active.
- A POWER_OK signal is generated when all critical supplies monitored by the LVD are available. This signal is active high and released to all modules including I/Os, flash

Table 20. Supply current (5.0 V, NVUSRO[PAD3V5V] = 0)

Symbol	C	Parameter	Conditions		Value ⁽¹⁾		Unit
					Typ	Max	
I _{DD_LV_CORx}	T	RUN—Maximum mode ⁽²⁾	V _{DD_LV_CORx} externally forced at 1.3 V	40 MHz	44	55	mA
	P			64 MHz	52	65	
	T	RUN—Typical mode ⁽³⁾		40 MHz	38	46	
				64 MHz	45	54	
	P	HALT mode ⁽⁴⁾		—	1.5	10	
		STOP mode ⁽⁵⁾		—	1	10	
I _{DD_FLASH}	T	Flash during read	V _{DD_HV_FL} at 5.0 V	—	8	10	
		Flash during erase operation on 1 flash module	V _{DD_HV_FL} at 5.0 V	—	15	19	
I _{DD_ADC}	T	ADC	V _{DD_HV_ADC0} at 5.0 V f _{ADC} = 16 MHz	ADC_0	3	4	
I _{DD_OSC}	T	Oscillator	V _{DD_HV_OSC} at 5.0 V	8 MHz	2.6	3.2	
I _{DD_HV_REG}	D	Internal regulator module current consumption	V _{DD_HV_REG} at 5.5 V		—	10	

1. All values to be confirmed after characterization/data collection.
2. Maximum mode: FlexPWM, ADC, CTU, DSPI, LINFlex, FlexCAN, 15 output pins, PLL_0 enabled, 125 °C ambient. I/O supply current excluded.
3. Typical mode configurations: DSPI, LINFlex, FlexCAN, 15 output pins, PLL_0, 105 °C ambient. I/O supply current excluded.
4. Halt mode configurations: Code fetched from SRAM, code flash memory and data flash memory in low power mode, OSC/PLL_0 are OFF, core clock frozen, all peripherals disabled.
5. STOP "P" mode Device Under Test (DUT) configuration: Code fetched from SRAM, code flash memory and data flash memory off, OSC/PLL_0 are OFF, core clock frozen, all peripherals disabled.

Table 26. Main oscillator output electrical characteristics (3.3 V, NVUSRO[PAD3V5V] = 1)

Symbol		C	Parameter	Conditions	Value		Unit
					Min	Max	
f _{OSC}	SR	—	Oscillator frequency		4	40	MHz
g _m	—	P	Transconductance		4	20	mA/V
V _{OSC}	—	T	Oscillation amplitude on XTAL pin		1	—	V
t _{OSCSU}	—	T	Start-up time ^{(1),(2)}		8	—	ms
C _L	CC	T	XTAL load capacitance ⁽³⁾	4 MHz	5	30	pf
		T		8 MHz	5	26	
		T		12 MHz	5	23	
		T		16 MHz	5	19	
		T		20 MHz	5	16	
		T		40 MHz	5	8	

1. The start-up time is dependent upon crystal characteristics, board leakage, etc. High ESR and excessive capacitive loads can cause long start-up time.
2. Value captured when amplitude reaches 90% of XTAL
3. This value is determined by the crystal manufacturer and board design. For 4 MHz to 40 MHz crystals specified for this oscillator, load capacitors should not exceed these limits.

Table 27. Input clock characteristics

Symbol	C	Parameter	Value			Unit
			Min	Typ	Max	
f_{OSC}	SR	Oscillator frequency	4	—	40	MHz
f_{CLK}	SR	Frequency in bypass	—	—	64	MHz
t_{rCLK}	SR	Rise/fall time in bypass	—	—	1	ns
t_{DC}	SR	Duty cycle	47.5	50	52.5	%

3.12 FMPLL electrical characteristics

Table 28. FMPLL electrical characteristics

Symbol	C	Parameter	Conditions ⁽¹⁾	Value		Unit
				Min	Max	
$f_{ref_crystal}$ f_{ref_ext}	D	PLL reference frequency range ⁽²⁾	Crystal reference	4	40	MHz
f_{PLLIN}	D	Phase detector input frequency range (after pre-divider)	—	4	16	MHz
$f_{FMPLLOUT}$	D	Clock frequency range in normal mode	—	16	64	MHz

4. During the sampling time the input capacitance C_S can be charged/discharged by the external source. The internal resistance of the analog source must allow the capacitance to reach its final voltage level within t_s . After the end of the sampling time t_s , changes of the analog input voltage have no effect on the conversion result. Values for the sample clock t_s depend on programming.
5. This parameter includes the sampling time t_s .
6. 20 MHz ADC clock. Specific prescaler is programmed on MC_PLL_CLK to provide 20 MHz clock to the ADC.
7. See [Figure 16](#).

3.15 Flash memory electrical characteristics

3.15.1 Program/Erase characteristics

Table 31. Program and erase specifications

Symbol	C	Parameter	Value				Unit
			Min	Typ ⁽¹⁾	Initial Max ⁽²⁾	Max ⁽³⁾	
$T_{wprogram}$	P	Word Program Time for data flash memory ⁽⁴⁾	—	30	70	500	μs
$T_{dwprogram}$	P	Double Word Program Time for code flash memory ⁽⁴⁾	—	22	50	500	μs
T_{BKPRG}	P	Bank Program (256 KB) ⁽⁴⁾⁽⁵⁾	—	0.73	0.83	17.5	s
	P	Bank Program (64 KB) ⁽⁴⁾⁽⁵⁾	—	0.49	1.2	4.1	s
$T_{16kpperase}$	P	16 KB Block Pre-program and Erase Time for code flash memory	—	300	500	5000	ms
		16 KB Block Pre-program and Erase Time for data flash memory	—	700	800	5000	
$T_{32kpperase}$	P	32 KB Block Pre-program and Erase Time	—	400	600	5000	ms
$T_{128kpperase}$	P	128 KB Block Pre-program and Erase Time	—	800	1300	7500	ms
t_{ESRT}	P	Program and erase specifications ⁽⁶⁾	10	—	—	—	ms

1. Typical program and erase times assume nominal supply values and operation at 25 °C. All times are subject to change pending device characterization.
2. Initial factory condition: < 100 program/erase cycles, 25 °C, typical supply voltage.
3. The maximum program and erase times occur after the specified number of program/erase cycles. These maximum values are characterized but not guaranteed.
4. Actual hardware programming times. This does not include software overhead.
5. Typical Bank programming time assumes that all cells are programmed in a single pulse. In reality some cells will require more than one pulse, adding a small overhead to total bank programming time (see "Initial Max" column).
6. Time between erase suspend resume and next erase suspend request.

Table 36. Output pin transition times (continued)

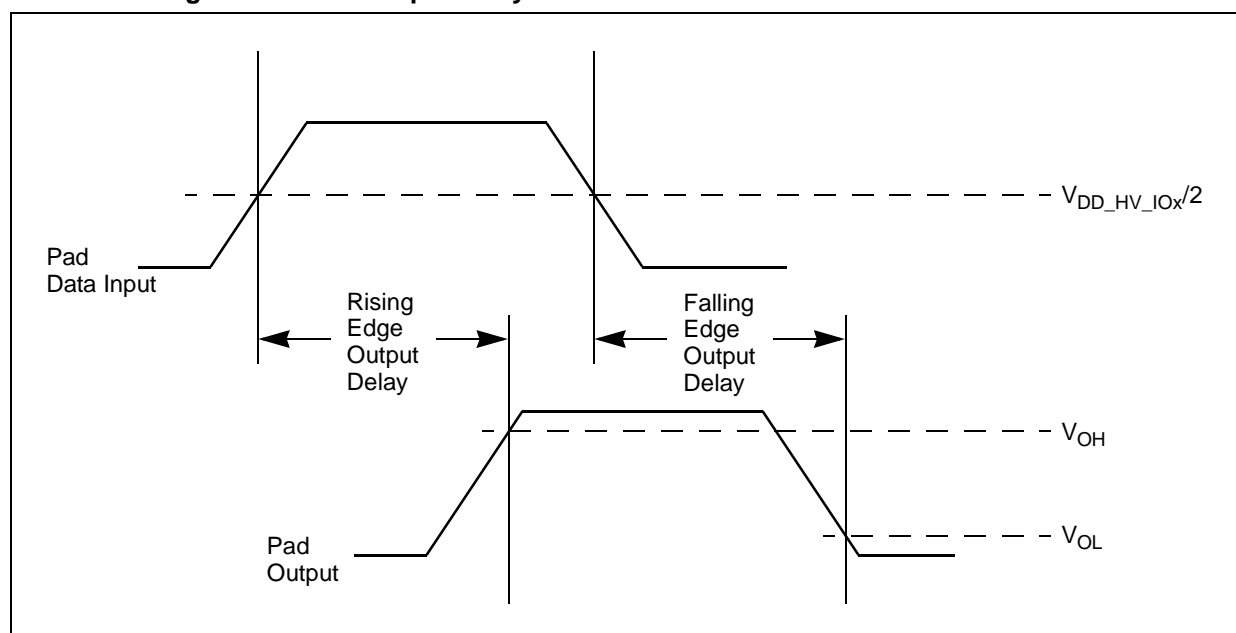
Symbol		C	Parameter	Conditions ⁽¹⁾		Value			Unit
						Min	Typ	Max	
t _{tr}	CC	D	Output transition time output pin ⁽²⁾ FAST configuration	C _L = 25 pF	V _{DD} = 5.0 V ± 10%, PAD3V5V = 0 SIUL.PCRx.SRC = 1	—	—	4	ns
				C _L = 50 pF		—	—	6	
				C _L = 100 pF		—	—	12	
				C _L = 25 pF	V _{DD} = 3.3 V ± 10%, PAD3V5V = 1 SIUL.PCRx.SRC = 1	—	—	4	
				C _L = 50 pF		—	—	7	
				C _L = 100 pF		—	—	12	
t _{SYM} ⁽³⁾	CC	T	Symmetric transition time, same drive strength between N and P transistor	V _{DD} = 5.0 V ± 10%, PAD3V5V = 0		—	—	4	ns
				V _{DD} = 3.3 V ± 10%, PAD3V5V = 1		—	—	5	

1. $V_{DD} = 3.3 \text{ V} \pm 10\%$ / $5.0 \text{ V} \pm 10\%$, $T_A = -40^\circ\text{C}$ to $T_{A \text{ MAX}}$, unless otherwise specified.

2. C_L includes device and package capacitances ($C_{PKG} < 5 \text{ pF}$).

3. Transition timing of both positive and negative slopes will differ maximum 50%.

Figure 19. Pad output delay



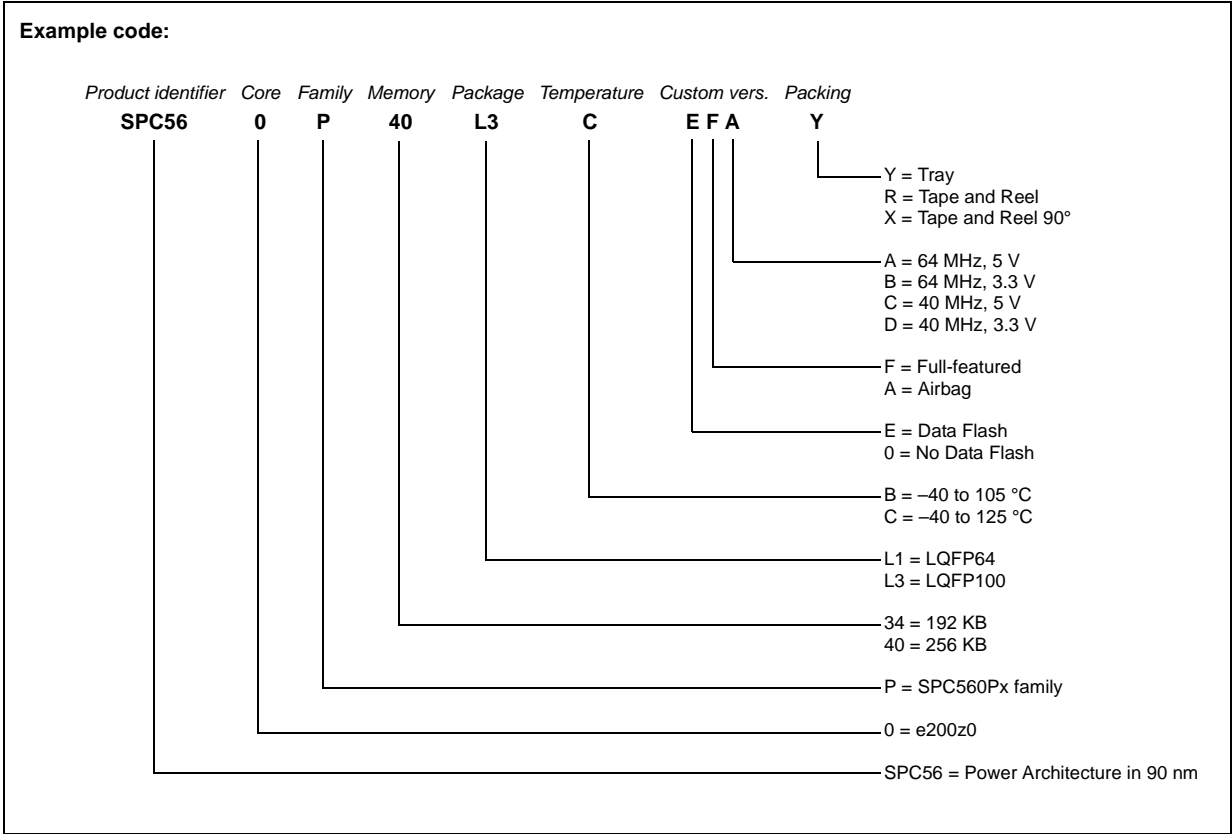
3.17 AC timing characteristics

3.17.1 $\overline{\text{RESET}}$ pin characteristics

The SPC560P34/SPC560P40 implements a dedicated bidirectional $\overline{\text{RESET}}$ pin.

5 Ordering information

Figure 40. Commercial product code structure



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